

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Eric Replogle on 9 October 2008.

The claims of 1 July 2008 have been changed as follows:

- Claim 25:
 - In lines 13-14: "if it is determined that the node is ~~[[a]]~~ the second terminating node of the optical circuit, the node signaling the first terminating node by removing a light of ~~the~~ a second wavelength..."
- Misnumbered claims 33-41 have been renumbered 31-39.
- Renumbered claim 39 (previously misnumbered claim 41):
 - In lines 13-14: "if it is determined that the node is ~~[[a]]~~ the second terminating node of the optical circuit, signal the first terminating node by removing a light of ~~the~~ a second wavelength..."

Conclusion

2. Any inquiry concerning this communication from the examiner should be directed to N. Curs whose telephone number is (571) 272-3028. The examiner can normally be reached on M-F (from 9 AM to 5 PM).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jason Chan, can be reached at (571) 272-3022. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pairedirect.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

/N. M. C./

Examiner, Art Unit 2613

/Jason Chan/

Supervisory Patent Examiner, Art Unit 2613